

Notice of References Cited	Application/Control No. 10/689,814	Applicant(s)/Patent Under Reexamination HASSNER ET AL.	
	Examiner R. Stephen Dildine	Art Unit 2133	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2005/0015700 A1	01-2005	Hetzler et al.	714/766
*	B	US-2004/0078642 A1	04-2004	Nanda, Sanjeeb	714/006
*	C	US-2003/0167439 A1	09-2003	Talagala et al.	714/770
*	D	US-6,675,318 B1	01-2004	Lee, Whay S.	714/770
*	E	US-6,167,552 A	12-2000	Gagnon et al.	714/760
*	F	US-3,831,144 A	08-1974	En, John	714/804
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	McCorkle, Mike; The International Electrotechnical Commission Standard for exponent prefixes in IT; Presented at the THIC Meeting at the National Center for Atmospheric Research, Boulder, CO June 29-30, 2004; cover sheet and pages 1-2; URL http://www.thic.org/pdf/Jun04/fujifilm.mmccorkle.pdf
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.